TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7SZ32AFE

#### 2 Input OR Gate

#### **Features**

• High output drive: ±24 mA (typ.)

$$@V_{CC} = 3 V$$

• Super high speed operation: tpD 2.4 ns (typ.)

$$@V_{CC} = 5 \text{ V}, 50 \text{ pF}$$

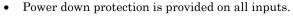
• Operation voltage range:  $V_{CC (opr)} = 1.8 \sim 5.5 \text{ V}$ 

• Supply voltage data retention:  $V_{CC} = 1.5 \sim 5.5 \text{ V}$ 

• Latch-up performance: ±500 mA

ESD performance: Human body model > ±2000 V

Machine model  $> \pm 200 \text{ V}$ 



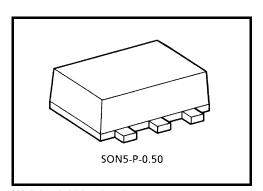
 $\bullet$  Matches the performance of TC74LCX series when operated at 3.3 V V<sub>CC</sub>

• Input rise and fall time (tr, tf) (recommended operation condition)

$$@V_{CC} = 1.8 \text{ V}, 2.5 \text{ V} \pm 0.2 \text{ V}$$
: 0~20 ns/V

 $@V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V} : 0 \sim 10 \text{ ns/V}$ 

 $@V_{CC} = 5.5 \text{ V} \pm 0.5 \text{ V}$ :  $0 \sim 5 \text{ ns/V}$ 



Weight: 0.003 g (typ.)

#### Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Supply voltage range	$V_{CC}$	-0.5~6	V
DC input voltage	V <sub>IN</sub>	-0.5~6	V
DC output voltage	V <sub>OUT</sub>	-0.5~V <sub>CC</sub> + 0.5	٧
Input diode current	l <sub>IK</sub>	±20	mA
Output diode current	lok	±20	mA
DC output current	lout	±50	mA
DC V <sub>CC</sub> /ground current	Icc	±50	mA
Power dissipation	PD	150	mW
Storage temperature	T <sub>stg</sub>	<b>−65~150</b>	°C
Lead temperature (10 s)	TL	260	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

# **Operating Ranges**

**TOSHIBA** 

Characteristics	Symbol	Rating	Unit	
Supply voltage	Voo	1.8~5.5	V	
Supply voltage	V <sub>CC</sub>	1.5~5.5 (Note 1)	V	
Input voltage	V <sub>IN</sub>	0~5.5	V	
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V	
Operating temperature	T <sub>opr</sub>	-40~85	°C	
		$0\sim20~(V_{CC}=1.8~V,~2.5~V\pm0.2~V)$	ns/V	
Input rise and fall time	dt/dv	$0 \sim 10 \; (V_{CC} = 3.3 \; V \pm 0.3 \; V)$		
		$0~5~(V_{CC} = 5.5~V \pm 0.5~V)$		

Note 1: Data retention only.

## **Electrical Characteristics**

## **DC Characteristics**

Test		<b>-</b>			Ta = 25°C Ta = -40~85°C			0~85°C					
Characteristics	Symbol	Circuit	Test Condition		V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Unit		
High-level input VIH —				1.8	0.75 × V <sub>CC</sub>	_	_	0.75 × V <sub>CC</sub>	_	V			
voltage	VIΗ		_		2.3- 5.5	0.7 × V <sub>CC</sub>	_	_	0.7 × V <sub>CC</sub>		V		
Low-level input	V <sub>IL</sub>							0.25 × V <sub>CC</sub>		0.25 × V <sub>CC</sub>	V		
voltage	VIL			_	2.3- 5.5	_	_	0.3 × V <sub>CC</sub>	_	0.3 × V <sub>CC</sub>	V		
					1.8	1.7	1.8	_	1.7				
				I <sub>OH</sub> = -100 μA	2.3	2.2	2.3	_	2.2				
				ΙΟΗ = -100 μΑ	3.0	2.9	3.0	_	2.9		V		
High-level	Voh		V <sub>IN</sub> = V <sub>IH</sub> or		4.5	4.4	4.5	_	4.4				
output voltage	VOH		VIL VIL	$I_{OH} = -8 \text{ mA}$	2.3	1.9	2.15	_	1.9				
				I <sub>OH</sub> = -16 mA	3.0	2.4	2.8	_	2.4				
				I <sub>OH</sub> = -24 mA	3.0	2.3	2.68	_	2.3				
							I <sub>OH</sub> = -32 mA	4.5	3.8	4.2	_	3.8	_
					1.8	_	0	0.1	_	0.1			
						$I_{OL} = 100 \ \mu A$	2.3	_	0	0.1	_	0.1	
							3.0	_	0	0.1	_	0.1	
Low-level output	Low-level output VOL —		V <sub>IN</sub> =		4.5	—	0	0.1	_	0.1	V		
voltage		V <sub>IL</sub>	I <sub>OL</sub> = 8 mA	2.3	_	0.1	0.3	_	0.3	V			
			I <sub>OL</sub> = 16 mA	3.0	_	0.15	0.4	_	0.4				
				I <sub>OL</sub> = 24 mA	3.0	_	0.22	0.55	_	0.55			
				I <sub>OL</sub> = 32 mA	4.5	—	0.22	0.55	_	0.55			
Input leakage current	I <sub>IN</sub>	_	V <sub>IN</sub> = 5.5 V or GND		0- 5.5	_	_	±1	_	±10	μΑ		
Quiescent supply current	Icc	_	V <sub>IN</sub> = V <sub>C</sub>	<sub>C</sub> or GND	5.5	_	_	2	_	20	μА		

2

#### AC Characteristics (input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Test	Test Condition		Ta = 25°C			Ta = -4	Unit	
Ciral acteristics Symbol Cir	Circuit	Circuit	V <sub>CC</sub> (V)	Min	Тур.	Max	Min	Max	Offic	
Propagation delay <sup>t</sup> PLH time <sup>t</sup> PHL				1.8	2.0	4.6	10.0	2.0	10.5	
	_	$C_L = 15 \text{ pF},$ $R_L = 1 \text{ M}\Omega$	$2.5\pm0.2$	0.8	3.0	7.0	0.8	7.5	- ns	
			$3.3 \pm 0.3$	0.5	2.4	4.7	0.5	5.0		
			5.0 ± 0.5	0.5	1.9	4.1	0.5	4.4		
		$\begin{array}{c} C_L = 50 \text{ pF}, \\ R_L = 500 \ \Omega \end{array}$	$3.3\pm0.3$	1.5	3.0	5.2	1.5	5.5		
			5.0 ± 0.5	0.8	2.4	4.5	8.0	4.8		
Input capacitance	C <sub>IN</sub>	_	_	0-5.5		4		_		pF
Power dissipation capacitance CP	Coo	C <sub>PD</sub> —	(Note)	3.3		19		_		- pF
	CPD			5.5	_	27	_	_	_	

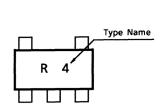
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

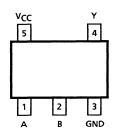
Average operating current can be obtained by the equation.

$$I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

# Marking

# Pin Assignment (top view)



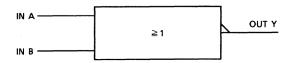


#### **Truth Table**

Α	В	Υ
L	L	L
L	Н	Н
Н	L	Н
Н	Н	Н

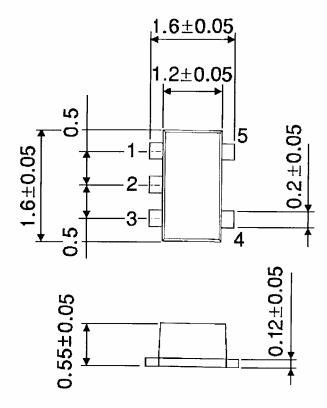
#### **Logic Diagram**

3



## **Package Dimensions**

SON5-P-0.50 Unit: mm



Weight: 0.003 g (typ.)

#### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

- The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
- The products described in this document shall not be used or embedded to any downstream products of which
  manufacture, use and/or sale are prohibited under any applicable laws and regulations.
- The information contained herein is presented only as a guide for the applications of our products. No
  responsibility is assumed by TOSHIBA for any infringements of patents or other rights of the third parties which
  may result from its use. No license is granted by implication or otherwise under any patents or other rights of
  TOSHIBA or the third parties.
- Please contact your sales representative for product-by-product details in this document regarding RoHS
  compatibility. Please use these products in this document in compliance with all applicable laws and regulations
  that regulate the inclusion or use of controlled substances. Toshiba assumes no liability for damage or losses
  occurring as a result of noncompliance with applicable laws and regulations.